

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	8411	inspect\$3 near3 object	USPAT	OR	ON	2006/06/06 17:26
L2	3052	L1 and (wafer\$I or semiconductor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring adj board or BGA or ball adj grid adj array or leads)	USPAT	OR	ON	2006/06/06 17:26
L3	3052	L1 and L2	USPAT	OR	ON	2006/06/06 17:26
L4	70	L3 and inspect\$3 near3 object and (ROI or region adj of adj interest)	USPAT	OR	ON	2006/06/06 17:32
L5	197	L3 and (plurality or plural\$I or set)and attributes and(template or prototype\$I or model or reference near3 image\$I or models)	USPAT	OR	ON	2006/06/06 17:29
L6	668	382/147,149,256.ccls.	USPAT	OR	ON	2006/06/06 17:30
L7	506	361/720.ccls.	USPAT	OR	ON	2006/06/06 17:30
L8	35	702/102.ccls.	USPAT	OR	ON	2006/06/06 17:30
L9	237	L6 and L1	USPAT	OR	ON	2006/06/06 17:31
L10	145	L9 and L2	USPAT	OR	ON	2006/06/06 17:31
L11	145	L10 and L3	USPAT	OR	ON	2006/06/06 17:31
L12	10	L11 and L5	USPAT	OR	ON	2006/06/06 17:31
L13	0	L12 and inspect\$3 near3 object and (ROI or region adj of adj interest)	USPAT	OR	ON	2006/06/06 17:32
L14	0	L7 and L1	USPAT	OR	ON	2006/06/06 17:32
L15	0	L14 and L2	USPAT	OR	ON	2006/06/06 17:33
L16	1	L8 and L1	USPAT	OR	ON	2006/06/06 17:33
L17	1	L16 and L2	USPAT	OR	ON	2006/06/06 17:33
L18	1	L17 and L3	USPAT	OR	ON	2006/06/06 17:33
L19	1	L18 and L5	USPAT	OR	ON	2006/06/06 17:34
L20	0	L19 and L4	USPAT	OR	ON	2006/06/06 17:34

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	(inspect\$3 near3 object and (wafer\$I or semiconductor\$I or chip\$I or substrat\$I or IC or intergrated adj circuit or PCB or printed adj circuit adj board or PWB or printed adj wiring adj board or BGA or ball adj grid adj array or leads)and structural adj model and geometric adj model).CLM.	US-PGPUB	OR	ON	2006/06/07 08:52